

Product Information Sheet

(August 2019)

Launched at the ECM32 in Vienna on August 18, 2019, the ELDICO **Electron Diffractometer** will enable crystallographers entering the sub- μm regime for single-crystal structure analysis of nano-crystalline particles. The (often) many crystallisation attempts for growing large-enough samples belong to the past.

Horizontal is the new normal

Other than transmission electron microscopes (TEM), the device is designed dedicated solely to Electron Diffraction (ED; also known as microED or tomography), allowing to outperform TEM in diffraction. With a disruptive horizontal design and an innovative probe handling mechanism, the dedicated Electron Diffractometer will support crystallographers to enter the field of nano-crystallography and produce important structural information faster, with better quality and at lower cost.



(Source: ELDICO)

Key facts of the ELDICO electron diffractometer

- Sample size from 10 to 1000 nm
- Radically simplified EM design
- Improved goniometer
- R_1 below 10%

The proof-of-concept was achieved in 2018 (ETH Zurich, C-CINA Basel) on scientifically and industrially relevant samples. Results published recently (Angewandte Chemie, International Edition) gained significant attention and were nominated for «Breakthrough of the Year 2018» by SCIENCE.

The launch of the first small batch series is expected for July 2020.

For more information please contact:

Dr. Eric Hovestreydt, CSO (hovestreydt@eldico.ch; +49 173 7000 615).